

Near Infrared Polariscopes

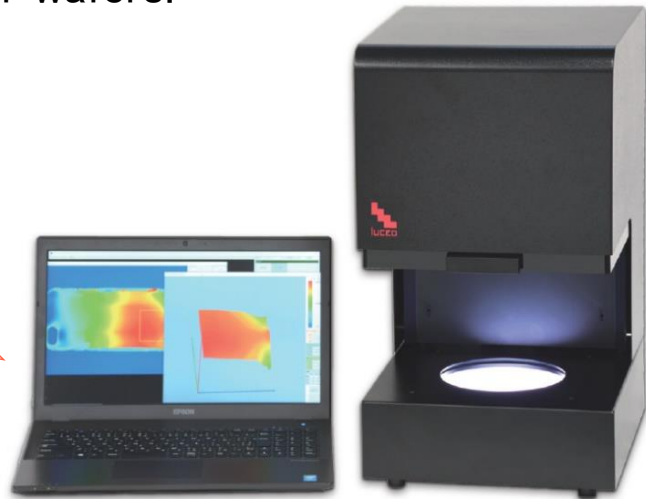
Fullauto StrainEye LSM-9001 NIR

- ✓ Evaluate strain distribution of Si, SiC, GaN and glass wafers
- ✓ Evaluation of 50 x 50mm area in 1 minute by plane distribution
- ✓ Evaluate strain distribution of colored glass and acrylic resin

Enables quality control of silicon wafer

■ This is a fully automatic polarimeter for low phase difference products such as semiconductor wafers.

We'll evaluate your samples anytime!



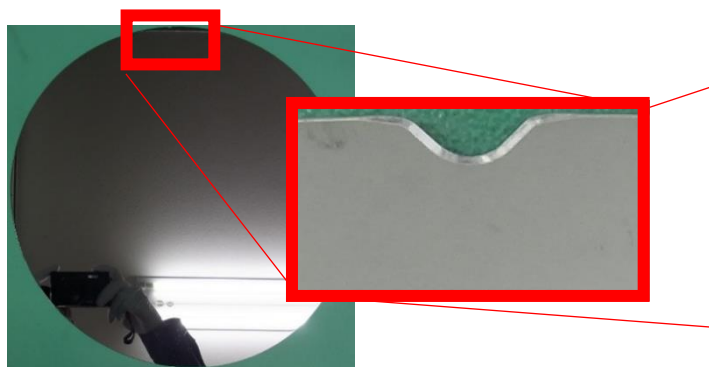
■ Target products

- Si / SiC / GaN / Glass wafer
- Transparent/colored resin products
- Crystallized quartz / Quartz / Optical crystals

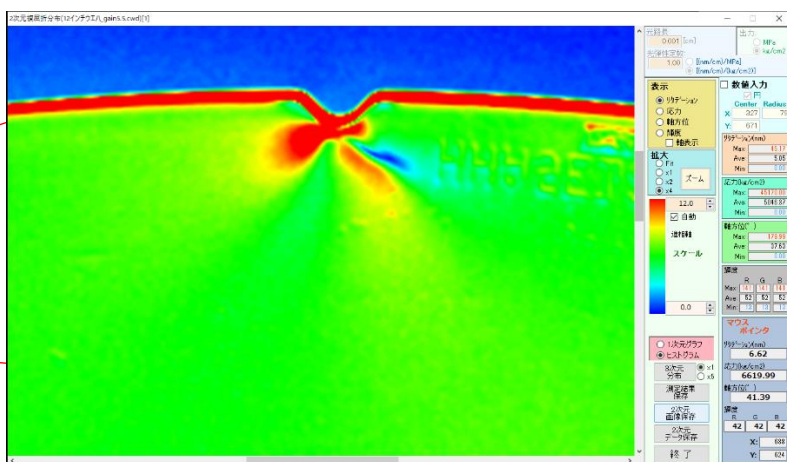
You can evaluate resin product like these colors!



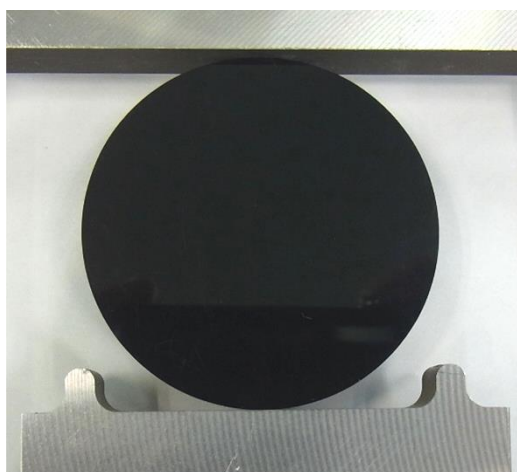
■ Evaluation Examples Silicon wafer / Colored acrylic resin molded



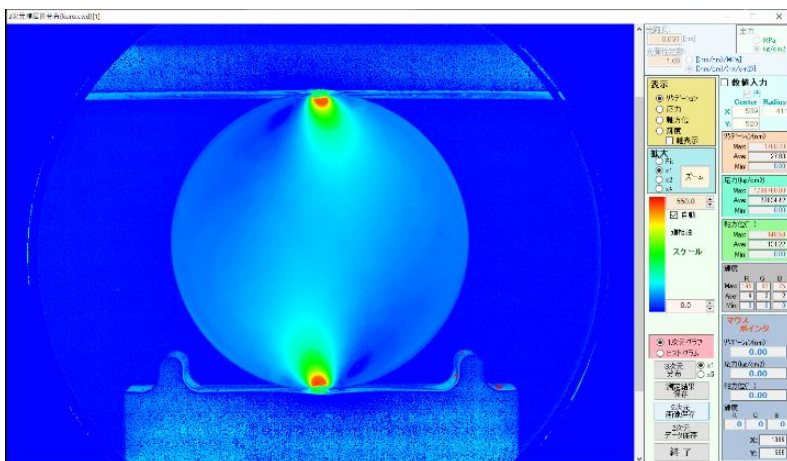
Silicon wafer Around the notch



Strain distribution (Residual stress in the grinding process)



Black acrylic resin disc under compressive load



Strain distribution

■ Specification

Specification	Near Infrared Polariscope LSM-9001NIR
Display items	Retardation (nm), Stress (MPa)
Measurement range	0~150nm
Measurement area size	Approx. 50 × 50mm
Inspection method	NIR Rotating Analyzer Method
Size / Weight (body)	W300 × D353 × H540mm / 22kg

We offer sample measurement service. There are a variety of polariscopes besides LSM-9001NIR. Please feel free to contact us via **"CONTACT US"**.

